



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

2825  
04-02-02

Re application of: Wayne Biao Liu

Attorney Docket No.: DSC1P003

Application No.: 09/938,708

Examiner: Not yet assigned

Filed: August 24, 2001

Group: 2825

Title: SPACE REDUCTION IN  
COMPOSITIONAL STATE SYSTEMS

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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, Washington, DC 20231 on February 20, 2002.

Signed: 

Tara Hayden

**INFORMATION DISCLOSURE STATEMENT**  
**37 CFR §§1.56 AND 1.97(b)**

Commissioner for Patents  
Washington, DC 20231

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Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. DSC1P003).

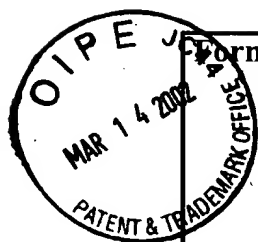
Respectfully submitted,

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<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. DSC1P003 Applicant: Wayne Biao Liu Filing Date August 24, 2001	Application No.: 09/938,708  Group 2825
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### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
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### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No
	A	WO 99/50746	07.10.99	PCT				

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### Other Documents

**MAR 26 2002**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	B	Holzmann, Gerald J., "The Model Checker Spin", IEEE Transactions on Software Engineering, Vol. 23, No. 5, May 1997, pp. 1-17.
	C	Norris, et al., "Better Verification Through Symmetry", Department of Computer Science, Stanford University, To appear in Formal Methods in System Design, Vol. 9, Numbers ½, 1996, pp. 1-34.
	D	Burch, et al., "Symbolic Model Checking: 10 <sup>20</sup> States and Beyond", School of Computer Science Carnegie Mellon University, Stanford University, June 1990, pp. 1-33.
	E	Graf, et al., "Compositional Minimization of Finite State Systems", In Proc 2 <sup>nd</sup> Workshop on Computer Aided Verification, Vol. 531 of Lecture Notes in Computer Science, Rutgers, June 1990, pp. 1-21.
	G	Godefroid, et al., "A Partial Approach to Model Checking", Information and Computation, Vol. 119, No. 2, Academic Press, May 1994, pp. 1-21.
	H	Cheung, et al., "Incorporation of Context Constraints for Compositional Reachability Analysis", Technical Report HKUST-CS96-5, Department of Computer Science, The Hong Kong University of Science and Technology, February 1996, pp. 1-40.
	I	Liu, Wayne, "Interaction Abstraction for Compositional Finite State Systems", Department of Electrical and Computer Engineering, Proceedings of the 7 <sup>th</sup> SPIN Workshop, University of Waterloo, Vol. 1885, September 2000, pp. 148-162.
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.